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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Obsolete
Core Processor	RL78
Core Size	16-Bit
Speed	24MHz
Connectivity	CSI, I ² C, LINbus, UART/USART
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	42
Program Memory Size	96KB (96K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	6K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 9x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f10wlfafa-v0

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

1.2 List of Part Numbers



Figure 1-1. Part Number, Memory Size, and Package of RL78/L13



- **Notes 1.** Total current flowing into V_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD} or V_{SS}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the LCD controller/driver, A/D converter, LVD circuit, comparator, I/O port, on-chip pull-up/pull-down resistors, and the current flowing during data flash rewrite.
 - 2. When high-speed on-chip oscillator and subsystem clock are stopped.
 - 3. When high-speed system clock and subsystem clock are stopped.
 - 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When setting ultra-low power consumption oscillation (AMPHS1 = 1). The current flowing into the LCD controller/driver, 16-bit timer KB20, real-time clock 2, 12-bit interval timer, and watchdog timer is not included.
 - 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below. HS (high-speed main) mode: $2.7 V \le V_{DD} \le 5.5 V@1 MHz$ to 24 MHz $2.4 V \le V_{DD} \le 5.5 V@1 MHz$ to 16 MHz
 - LS (low-speed main) mode: $1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}_{\odot}$ 1 MHz to 8 MHz
 - LV (low-voltage main) mode: $1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}_{\odot} 1 \text{ MHz}$ to 4 MHz
- **Remarks 1.** fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fHOCO: High-speed on-chip oscillator clock frequency (48 MHz max.)
 - 3. fin: High-speed on-chip oscillator clock frequency (24 MHz max.)
 - **4.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 5. Except subsystem clock operation, temperature condition of the TYP. value is $T_A = 25^{\circ}C$



$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

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Parameter	Symbol	ļ	Conditior		MIN.	TYP.	MAX.	Unit	
Low-speed on-	FILNote 1						0.20		μA
chip oscillator									
operating current	Notice 1 2					<u> </u>			<u> </u>
RTC2 operating current	IRTC ^{Notes 1, 2,} 3	fsuв = 32.768 kHz					0.02		μA
12-bit interval	ITMKA ^{Notes 1, 2,}						0.04		μA
timer operating	4								
current									
Watchdog timer	WDT ^{Notes 1, 2, 5}	fı∟ = 15 kHz					0.22		μA
operating current		ļ							
A/D converter	ADC ^{Notes 1, 6}	When conversion	Normal mode	e, AV _{REFP} = V _{DI}	D = 5.0 V		1.3	1.7	mA
operating current		at maximum speed	Low voltage r	node, AV _{REFP}	= V _{DD} = 3.0 V		0.5	0.7	mA
A/D converter	ADREF ^{Note 1}						75.0		μA
reference voltage									
Tomperature	ITMOO Note 1						75.0		Δ
sensor operating	TIMPS						10.0		μη
current		l							
LVD operating	LVDNotes 1, 7						0.08		μA
current		<u> </u>							
Comparator	ICMP ^{Notes 1, 11}	V _{DD} = 5.0 V,	= 5.0 V, Window mode						μA
operating current		Regulator output	Comparator h	igh-speed mo	ode	<u> </u>	6.5		μA
			Comparator low-speed mode						μA
		V _{DD} = 5.0 V,		8.0		μA			
		Regulator output	Comparator h	igh-speed mo	ode	Γ	4.0		μA
	!	Voltage = 1.0 v	Comparator lo	ow-speed mod	de		1.3		μA
Self-	FSPNotes 1, 9						2.00	12.20	mA
programming									
operating current	Notes 1.9		<u> </u>						
BGO operating current	BGO ^{Notes 1, 6}						2.00	12.20	MA
SNOOZE	ISNOZ ^{Note 1}	ADC operation	While the more	de is shifting ^N	ote 10		0.50	0.60	mA
operating current			During A/D cc	onversion, in le	ow voltage		1.20	1.44	mA
			mode, AVREFP	· = V _{DD} = 3.0 V	/				
		CSI/UART operation	1	-			0.70	0.84	mA
LCD operating	LCD1 Notes 1, 12,	External resistance	fLCD = fSUB	1/3 bias,	V _{DD} = 5.0 V,		0.04	0.20	μA
current	13	division method	LCD clock =	four time	V _{L4} = 5.0 V				
			128 Hz	slices					<u> </u>
	LCD2 ^{Note 1, 12}	Internal voltage	fLCD = fSUB	1/3 bias,	V _{DD} = 3.0 V,		0.85	2.20	μA
		boosting method	LCD clock =	four time	V _{L4} = 3.0 V				
			128 Hz	slices	(V _{LCD} = 04H)				
					$V_{DD} = 5.0 V,$		1.55	3.70	μA
			ļ		$V_{L4} = 5.1 V$				
	· Note 1 12				$(VLCD = 12\Pi)$				
	LCD3	Capacitor split	fLCD = fsuB	1/3 blas,	$V_{DD} = 3.0 V,$		0.20	0.50	μA
		method	128 Hz	slices	VL4 - 0.0 V				

(Notes and Remarks are listed on the next page.)



Parameter	Symbol	Co	Conditions			LS (low-s main) N	speed /lode	LV (low-vo main) M	oltage lode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.$.5 V	167 ^{Note 1}		500 ^{Note 1}		1000 ^{Note 1}		ns
		$2.4~V \le V_{\text{DD}} \le 5.$	$4 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$			500 ^{Note 1}		1000 ^{Note 1}		ns
		$1.8~V \le V_{\text{DD}} \le 5.$.5 V	_		500 ^{Note 1}		1000 ^{Note 1}		ns
		$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.$	-		_		1000 ^{Note 1}		ns	
SCKp high-/low-level	t кн1,	$4.0~V \le V_{\text{DD}} \le 5.$.5 V	tkcy1/2-12		tkcy1/2-50		tkcy1/2-50		ns
width	t ĸ∟1	$2.7~V \leq V_{\text{DD}} \leq 5.$	$7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			tkcy1/2-50		tkcy1/2-50		ns
		$2.4~V \le V_{\text{DD}} \le 5.$.5 V	tkcy1/2-38		tkcy1/2-50		tkcy1/2-50		ns
		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.$.5 V	_		tkcy1/2-50		tkcy1/2-50		ns
		$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.$.5 V	-		-		tkcy1/2-100		ns
SIp setup time	tsik1	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.$.5 V	44		110		110		ns
(to SCKp↑) ^{Note 2}		$2.4~V \le V_{\text{DD}} \le 5.$.5 V	75		110		110		ns
		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.$.5 V	-		110		110		ns
		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.$.5 V	-		_		220		ns
SIp hold time	tksi1	$2.4~V \leq V_{\text{DD}} \leq 5.$.5 V	19		19		19		ns
(from SCKp [↑]) ^{Note 3}		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.$.5 V	-		19		19		ns
		$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.$	$1.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			_		19		ns
Delay time from	tkso1	C = 30 pF ^{Note 5}	$c = 30 \text{ pF}^{\text{Note 5}}$ 2.4 V \leq V _{DD} \leq 5.5 V				25		25	ns
SCKp↓ to			$1.8~V \leq V_{\text{DD}} \leq 5.5~V$		-		25		25	ns
SOp output ^{Note 4}			$1.6~V \le V_{\text{DD}} \le 5.5~V$		_		_		25	ns

(2)	During communication at same potential (CSI mode) (master mode, SCKp internal clock output
	$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

Notes 1. The value must also be equal to or more than 2/fcLk for CSI00 and equal to or more than 4/fcLk for CSI10.

- **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp \downarrow " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp \downarrow " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00, 10), m: Unit number (m = 0), n: Channel number (n = 0, 2), g: PIM and POM numbers (g = 0, 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02))





CSI mode connection diagram (during communication at same potential)

CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)





2. m: Unit number, n: Channel number (mn = 00, 02)



(6) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

Parameter	Symbol		Conditions			LS (low-speed main) Mode		LV (low main)	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tксүı	tксү1 ≥ 2 /fc∟к		200		1150		1150		ns
			$\label{eq:2.7} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 20 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	300		1150		1150		ns
SCKp high-level width	tкнı	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ pF, \ R_{\text{b}} \end{array} \end{array}$	5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ	tксү1/2 — 50		tксү1/2 — 50		tксү1/2 — 50		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.$ $C_{\text{b}} = 20 \text{ pF}, \text{ R}_{\text{b}} = 10 \text{ pF}$	0 V, 2.3 V ≤ V _b ≤ 2.7 V, = 2.7 kΩ	tксү1/2 — 120		tксү1/2 — 120		tксү1/2 — 120		ns
SCKp low-level width	tĸ∟1	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ pF, \ R_{\text{b}} = \end{array}$	5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ	tксү1/2 — 7		tксү1/2 — 50		tксү1/2 — 50		ns
		$2.7 V \le V_{DD} < 4.$ C _b = 20 pF, R _b =	$ \begin{array}{l} \hline c_{D} & 2.0 \ \text{p}^{-1}, \ \text{Ho} & 1.1 \ \text{Kal} \\ \hline 2.7 \ \text{V} \leq V_{\text{DD}} < 4.0 \ \text{V}, \ 2.3 \ \text{V} \leq V_{\text{b}} \leq 2.7 \ \text{V}, \\ \hline C_{\text{b}} = 20 \ \text{pF}, \ R_{\text{b}} = 2.7 \ \text{k}\Omega \end{array} $			tксү1/2 — 50		tксү1/2 — 50		ns
SIp setup time (to SCKp↑) ^{Note 1}	tsiĸ1	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ pF, \ R_{\text{b}} = \end{array}$	4.0 V \leq V _{DD} \leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V, C _b = 20 pF, R _b = 1.4 k Ω			479		479		ns
		$\begin{array}{l} 2.7 \; V \leq V_{\text{DD}} < 4.0 \; V, 2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ C_{b} = 20 \; pF, \; R_{b} = 2.7 \; k\Omega \end{array}$		121		479		479		ns
SIp hold time (from SCKp↑) ^{Note}	tksi1	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ pF, \ R_{\text{b}} \end{array} \end{array} \label{eq:eq:constraint}$	5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ	10		10		10		ns
1		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.$ $C_{\text{b}} = 20 \text{ pF}, \text{ R}_{\text{b}} = 10 \text{ pF}$	0 V, 2.3 V ≤ V₅ ≤ 2.7 V, = 2.7 kΩ	10		10		10		ns
Delay time from SCKp↓ to	tkso1	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ pF, \ R_{\text{b}} \end{array} \end{array}$	5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ		60		60		60	ns
SOp output ^{Note 1}		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.$ $C_{\text{b}} = 20 \text{ pF}, \text{ R}_{\text{b}} = 10 \text{ pF}$	0 V, 2.3 V ≤ V₅ ≤ 2.7 V, = 2.7 kΩ		130		130		130	ns
SIp setup time (to SCKp↓) ^{Note 2}	tsik1	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ pF, \ R_{\text{b}} = \end{array}$	5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ	23		110		110		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 4.$ C _b = 20 pF, R _b =	0 V, 2.3 V ≤ V₅ ≤ 2.7 V, = 2.7 kΩ	33		110		110		ns
SIp hold time (from SCKp↓) ^{Note}	tksi1	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ pF, \ R_{\text{b}} = \end{array}$	5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ	10		10		10		ns
2		$2.7 V \le V_{DD} < 4.$ C _b = 20 pF, R _b =	0 V, 2.3 V \leq V _b \leq 2.7 V, = 2.7 kΩ	10		10		10		ns
Delay time from SCKp↑ to	tkso1	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5. \\ C_{\text{b}} = 20 \ p\text{F}, \ R_{\text{b}} = \end{array} \end{array}$	5 V, 2.7 V \leq V _b \leq 4.0 V, = 1.4 kΩ		10		10		10	ns
SOp output ^{Note 2}		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.$ $C_{\text{b}} = 20 \text{ pF}, \text{ R}_{\text{b}} = 10 \text{ pF}$	0 V, 2.3 V \leq V _b \leq 2.7 V, = 2.7 kΩ		10		10		10	ns

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

(Notes, Caution and Remarks are listed on the next page.)

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0),
 g: PIM and POM number (g = 1)
 - **3.** fMCK: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))
 - 4. This specification is valid only when CSI00's peripheral I/O redirect function is not used.



(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (1/2) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

Parameter	Symbol		Conditions H			LS (low main)	/-speed Mode	LV (low main)	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t ксү1	tксү1 ≥ 4/fc∟к		300		1150		1150		ns
			$\label{eq:2.7} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	500		1150		1150		ns
			$ \begin{split} & 1.8 \; \text{V} \; (2.4 \; \text{V}^{\text{Note 1}}) \leq \text{V}_{\text{DD}} < 3.3 \\ & \text{V}, \\ & 1.6 \; \text{V} \leq \text{V}_{\text{b}} \leq 1.8 \; \text{V}^{\text{Note 2}}, \\ & \text{C}_{\text{b}} = 30 \; \text{pF}, \; \text{R}_{\text{b}} = 5.5 \; \text{k}\Omega \end{split} $	1150		1150		1150		ns
SCKp high-level width	t кн1	$\begin{array}{l} 4.0 \ V \leq V_{DD} \leq \\ C_b \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	5.5 V, 2.7 V \leq V _b \leq 4.0 V, _b = 1.4 kΩ	tксү1/2 — 75		tксү1/2 — 75		tксү1/2 — 75		ns
		2.7 V ≤ V _{DD} < C _b = 30 pF, R	4.0 V, 2.3 V \leq V _b \leq 2.7 V, h = 2.7 kΩ	tксү1/2 — 170		tксү1/2 — 170		tксү1/2 — 170		ns
		$1.8 V (2.4 V^{No})$ $1.6 V \le V_b \le 2$ $C_b = 30 \text{ pF, R}$	$\begin{array}{l} C_{b} = 30 \text{ pF}, \text{R}_{b} = 2.7 \text{k}\Omega \\ \hline 1.8 \text{ V} (2.4 \text{ V}^{\text{Note 1}}) \leq \text{V}_{\text{DD}} < 3.3 \text{ V}, \\ 1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V}^{\text{Note 2}}, \\ C_{b} = 30 \text{ pF}, \text{R}_{b} = 5.5 \text{k}\Omega \end{array}$			tксү1/2 — 458		tксү1/2 — 458		ns
SCKp low-level width	tĸ∟1	$4.0 V \le V_{DD} \le C_b = 30 pF, R$	5.5 V, 2.7 V \leq V _b \leq 4.0 V, h = 1.4 kΩ	tксү1/2 — 12		tксү1/2 — 50		tксү1/2 — 50		ns
		2.7 V ≤ V _{DD} < C _b = 30 pF, R	4.0 V, 2.3 V \leq V _b \leq 2.7 V, h = 2.7 kΩ	tксү1/2 — 18		tксү1/2 — 50		tксү1/2 — 50		ns
		1.8 V (2.4 V ^{NG} 1.6 V \leq V _b \leq 2 C _b = 30 pF, R	$V^{\text{te 1}}) \le V_{\text{DD}} < 3.3 \text{ V},$ 2.0 V ^{Note 2} , $V_{\text{b}} = 5.5 \text{ k}\Omega$	tксү1/2 — 50		tксү1/2 — 50		tксү1/2 — 50		ns
SIp setup time (to SCKp↑) ^{Note 3}	tsik1	$4.0 V \le V_{DD} \le C_b = 30 pF, R$	5.5 V, 2.7 V \leq V _b \leq 4.0 V, _b = 1.4 kΩ	81		479		479		ns
		$2.7 V \le V_{DD} < C_b = 30 pF, R$	4.0 V, 2.3 V \leq V _b \leq 2.7 V, h _b = 2.7 kΩ	177		479		479		ns
		$1.8 V (2.4 V^{NG})$ $1.6 V \le V_b \le 2$ $C_b = 30 \text{ pF, R}$	$V^{\text{tot 1}}) \le V_{\text{DD}} < 3.3 \text{ V},$ 2.0 V ^{Note 2} , $V_{\text{b}} = 5.5 \text{ k}\Omega$	479		479		479		ns
SIp hold time (from SCKp↑) ^{Note}	tksi1	$4.0 V \le V_{DD} \le C_b = 30 pF, R$	5.5 V, 2.7 V \leq V _b \leq 4.0 V, _b = 1.4 kΩ	19		19		19		ns
3		$2.7 V \le V_{DD} < C_b = 30 pF, R$	4.0 V, 2.3 V \leq V _b \leq 2.7 V, h _b = 2.7 kΩ	19		19		19		ns
		$\begin{array}{l} 1.8 \ V \ (2.4 \ V^{No} \\ 1.6 \ V \leq V_b \leq 2 \\ C_b = 30 \ pF, \ R \end{array}$	$V_{DD}^{\text{tot 1}} = V_{DD} < 3.3 \text{ V},$ 2.0 V ^{Note 2} , $V_{b} = 5.5 \text{ k}\Omega$	19		19		19		ns
Delay time from SCKp↓ to	tkso1	$\begin{array}{l} 4.0 \ V \leq V_{DD} \leq \\ C_b = 30 \ pF, \ R \end{array}$	5.5 V, 2.7 V \leq V _b \leq 4.0 V, hb = 1.4 k Ω		100		100		100	ns
SOp output ^{Note 3}		2.7 V ≤ V _{DD} < C _b = 30 pF, R	4.0 V, 2.3 V \leq V _b \leq 2.7 V, h _b = 2.7 kΩ		195		195		195	ns
		$\begin{array}{l} 1.8 \ V \ (2.4 \ V^{No} \\ 1.6 \ V \leq V_b \leq 2 \\ C_b = 30 \ pF, \ R \end{array}$	$\frac{(1)}{100000000000000000000000000000000000$		483		483		483	ns

(Notes and Caution are listed on the next page, and Remarks are listed on the page after the next page.)



Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- When AV_{REFP} < V_{DD}, the MAX. values are as follows.
 Overall error: Add ±4 LSB to the MAX. value when AV_{REFP} = V_{DD}.
 Zero-scale error/Full-scale error: Add ±0.2%FSR to the MAX. value when AV_{REFP} = V_{DD}.
 Integral linearity error/ Differential linearity error: Add ±2 LSB to the MAX. value when AV_{REFP} = V_{DD}.
 Values when the conversion time is set to 57 μs (min.) and 95 μs (max.).
- 5. See 2.6.2 Temperature sensor/internal reference voltage characteristics.
- (2) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V_{ss} (ADREFM = 0), target pins: ANI0, ANI1, ANI16 to ANI25, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{V}_{DD}, \text{ Reference voltage (-)} = \text{V}_{SS})$

Parameter	Symbol	Co	nditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Notes 1, 2}	AINL	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$		1.2	±7.0	LSB
			$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 3}}$		1.2	±10.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.125		39	μs
		Target pin: ANI0, ANI1, ANI16 to ANI25 ^{Note 3}	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.1875		39	μs
			$1.8~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs
			$1.6~V \leq V_{\text{DD}} \leq 5.5~V$	57		95	μs
		10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.5625		39	μs
reference voltage, a temperature sensor output voltage (HS (high-speed ma mode)		reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 3}}$			±0.85	%FSR
Full-scale errorNotes 1, 2	Efs	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 3}}$			±0.85	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±4.0	LSB
			$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 3}}$			±6.5	LSB
Differential linearity error Note	DLE	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±2.0	LSB
1			$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 3}}$			±2.5	LSB
Analog input voltage	VAIN	ANI0, ANI1, ANI16 to A	NI25	0		Vdd	V
Internal refere (2.4 V \leq V _{DD} \leq		Internal reference voltation (2.4 V \leq V _{DD} \leq 5.5 V, HS	ge S (high-speed main) mode))		VBGR ^{Note 4}		V
		Temperature sensor ou (2.4 V \leq V _{DD} \leq 5.5 V, HS	The function of the function				V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- **2.** This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Values when the conversion time is set to 57 μ s (min.) and 95 μ s (max.).
- 4. See 2.6.2 Temperature sensor/internal reference voltage characteristics.



LVD Detection Voltage of Interrupt & Reset Mode

(TA = -40 to +85°C, VPDR \leq VDD \leq 5.5 V, Vss = 0 V)

Parameter	Symbol		Cond	ditions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	VLVD13	Vpoc2,	VPOC1, VPOC0 = 0, 0, 0,	falling reset voltage	1.60	1.63	1.66	V
mode	VLVD12		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.74	1.77	1.81	V
				Falling interrupt voltage	1.70	1.73	1.77	V
	VLVD11		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.84	1.88	1.91	V
				Falling interrupt voltage	1.80	1.84	1.87	V
	VLVD4		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	VLVD11	Vpoc2,	VPOC1, VPOC0 = 0, 0, 1,	falling reset voltage	1.80	1.84	1.87	V
	VLVD10		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.02	V
				Falling interrupt voltage	1.90	1.94	1.98	V
	VLVD9	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.13	V	
			Falling interrupt voltage	2.00	2.04	2.08	V	
-	VLVD2	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.19	V	
				Falling interrupt voltage	3.00	3.06	3.12	V
	VLVD8	Vpoc2,	VPOC1, VPOC0 = 0, 1, 0,	2.40	2.45	2.50	V	
	VLVD7	VLVD7	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.66	V
				Falling interrupt voltage	2.50	2.55	2.60	V
	VLVD6		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.76	V
				Falling interrupt voltage	2.60	2.65	2.70	V
	VLVD1		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.68	3.75	3.82	V
				Falling interrupt voltage	3.60	3.67	3.74	V
	VLVD5	Vpoc2,	VPOC1, VPOC0 = 0, 1, 1,	falling reset voltage	2.70	2.75	2.81	V
	VLVD4		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	VLVD3		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.08	V
				Falling interrupt voltage	2.90	2.96	3.02	V
	VLVD0		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.98	4.06	4.14	V
				Falling interrupt voltage	3.90	3.98	4.06	V

2.6.6 Supply voltage rising slope characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
VDD rising slope	SVDD				54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V_{DD} reaches the operating voltage range shown in 2.4 AC Characteristics.



RL78/L13

2.11 Timing Specifications for Switching Flash Memory Programming Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset must be released before the external reset is released.	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset must be released before the external reset is released.	1			ms

$(T_A = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and completion the baud rate setting.
- **Remark** tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.
 - $t_{\text{su:}}$ Time to release the external reset after the TOOL0 pin is set to the low level
 - thD: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)



Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	P00 to P07, P10 to P17, P22 to P27, P30 to P35, P40 to P47, P50 to P57, P70 to P77, P125 to P127, P130, P137	Normal input buffer	0.8Vdd		Vdd	V
	VIH2	P03, P05, P06, P16, P17, P34, P43, P44, P46, P47, P53, P55	TTL input buffer 4.0 V \leq V _{DD} \leq 5.5 V	2.2		Vdd	V
			TTL input buffer $3.3 \text{ V} \leq \text{V}_{\text{DD}} < 4.0 \text{ V}$	2.0		Vdd	V
			TTL input buffer 2.4 V \leq V _{DD} $<$ 3.3 V	1.5		V _{DD}	V
	Vінз	P20, P21		0.7Vdd		VDD	V
	VIH4	P60, P61	0.7Vdd		6.0	V	
	VIH5	P121 to P124, P137, EXCLK, EXCLKS	, RESET	0.8VDD		VDD	V
Input voltage, low	VIL1	P00 to P07, P10 to P17, P22 to P27, P30 to P35, P40 to P47, P50 to P57, P70 to P77, P125 to P127, P130, P137	Normal input buffer	0		0.2V _{DD}	V
	VIL2	P03, P05, P06, P16, P17, P34, P43, P44, P46, P47, P53, P55	TTL input buffer 4.0 V \leq V _{DD} \leq 5.5 V	0		0.8	V
			TTL input buffer $3.3 \text{ V} \leq \text{V}_{\text{DD}} < 4.0 \text{ V}$	0		0.5	V
			TTL input buffer 2.4 V \leq V _{DD} $<$ 3.3 V	0		0.32	V
	VIL3	P20, P21		0		0.3Vdd	V
	VIL4	P60, P61	0		0.3VDD	V	
	VIL5	P121 to P124, P137, EXCLK, EXCLKS	, RESET	0		0.2V _{DD}	V

(TA = -40 to +105°C, 2.4 V \leq VDD \leq 5.5 V, Vss = 0 V)

- Caution The maximum value of V_I of pins P00, P04 to P07, P16, P17, P35, P42 to P44, P46, P47, P53 to P56, and P130 is V_{DD}, even in the N-ch open-drain mode.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



3.4 AC Characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol		Со	nditions		MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсч	Main system	HS (high-speed $2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5$		$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	0.0417		1	μs
instruction execution time)		clock (fmain) operation	main) m	ode	$2.4~V \leq V_{DD} < 2.7~V$	0.0625		1	μs
		$\begin{array}{llllllllllllllllllllllllllllllllllll$			28.5	30.5	31.3	μs	
		In the self HS (hig	HS (high	n-speed	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	0.0417		1	μs
		programming mode	main) m	ode	$2.4~V \leq V_{\text{DD}} < 2.7~V$	0.0625		1	μs
External system clock	f _{EX}	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5$	$V \le V_{DD} \le 5.5 V$			1.0		20.0	MHz
frequency		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2$	2.7 V			1.0		16.0	MHz
	fexs					32		35	kHz
External system clock input	texн, texL	$2.7~V \le V_{\text{DD}} \le 5$	5.5 V			24			ns
high-level width, low-level		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2$	2.7 V			30			ns
wiath	texns, texls	EXLS				13.7			μs
TI00 to TI07 input high-level width, low-level width	t⊤ıн, t⊤ı∟								ns
TO00 to TO07, TKBO00 ^{Note} ,	fто	HS (high-speed main) mode		4.0 V ≤	$V_{\text{DD}} \leq 5.5 \text{ V}$			12	MHz
TKBO01-0 to TKBO01-2 ^{Note}				$2.7~V \leq V_{\text{DD}} < 4.0~V$				8	MHz
output frequency				$2.4 \text{ V} \leq \text{V}_{\text{DD}}$ < 2.7 V				4	MHz
PCLBUZ0, PCLBUZ1 output	f PCL	HS (high-spee	d main)	4.0 V ≤	$V_{\text{DD}} \leq 5.5 \text{ V}$			16	MHz
frequency		mode		2.7 V ≤	V _{DD} < 4.0 V			8	MHz
				2.4 V ≤	V _{DD} < 2.7 V			4	MHz
Interrupt input high-level width, low-level width	tinth, tintl	INTP0 to INTP	7	2.4 V ≤	$V_{\text{DD}} \leq 5.5 \; V$	1			μs
Key interrupt input high-level width, low-level width	tkrh, tkrl	KR0 to KR7		2.4 V ≤	$V_{\text{DD}} \leq 5.5 \; V$	250			ns
IH-PWM output restart input high-level width	tihr	INTP0 to INTP	7			2			fсık
TMKB2 forced output stop input high-level width	tihr	INTP0 to INTP	2			2			fclk
RESET low-level width	trsl					10			μs

(Note and Remark are listed on the next page.)



Note Specification under conditions where the duty factor is 50%.

Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKSmn0, CKSmn1 bits of timer mode register mn (TMRmn) m: Unit number (m = 0), n: Channel number (n = 0 to 7))

Minimum Instruction Execution Time during Main System Clock Operation



AC Timing Test Points



External System Clock Timing





Simplified I²C mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



- **Remarks 1.** R_b[Ω]: Communication line (SDAr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance
 - **2.** r: IIC number (r = 00, 10), g: PIM and POM number (g = 0, 1)
- <R>
- 3. fmck: Serial array unit operation clock frequency
 - (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0), n: Channel number (n = 0-3), mn = 00-03, 10-13)



(3) When reference voltage (+) = internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pins: ANI0, ANI16 to ANI25

(T_A = -40 to +105°C, 2.4 V \leq V_{DD} \leq 5.5 V, V_{SS} = 0 V, Reference voltage (+) = V_{BGR}^{Note 3}, Reference voltage (-) = AV_{REFM}^{Note 4} = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES				8		bit
Conversion time	t CONV	8-bit resolution	$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	8-bit resolution	$2.4~V \leq V \text{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity error ^{Note 1}	ILE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error ^{Note 1}	DLE	8-bit resolution	$2.4~V \leq V\text{DD} \leq 5.5~V$			±1.0	LSB
Analog input voltage	VAIN			0		VBGRNote 3	V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. See 3.6.2 Temperature sensor/internal reference voltage characteristics.

3.6.2 Temperature sensor/internal reference voltage characteristics

(TA = -40 to +105°C, 2.4 V \leq VDD \leq 5.5 V, Vss = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	ADS register = 80H, T _A = +25°C		1.05		V
Internal reference output voltage	VBGR	ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tамр				5	μs



(2) 1/4 bias method

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	VL1	C1 to C5 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 μ F ^{Note 2}	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
Doubler output voltage	VL2	C1 to C5 ^{Note 1} =	0.47 <i>μ</i> F	2 VL1-0.08	2 VL1	2 VL1	V
Tripler output voltage	VL3	C1 to C5 ^{Note 1} =	0.47 <i>μ</i> F	3 VL1-0.12	3 VL1	3 VL1	V
Quadruply output voltage	VL4	C1 to C5 ^{Note 1} =	0.47 <i>μ</i> F	4 VL1-0.16	4 VL1	4 VL1	V
Reference voltage setup time ^{Note 2}	tvwait1			5			ms
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C5 ^{Note 1} =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between V_{L1} and GND
- C3: A capacitor connected between V_{L2} and GND
- C4: A capacitor connected between $V_{\mbox{\tiny L3}}$ and GND
- C5: A capacitor connected between $V_{{\scriptscriptstyle L4}}$ and GND
- C1 = C2 = C3 = C4 = C5 = 0.47 μ F ± 30%
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

3.7.3 Capacitor split method

(1) 1/3 bias method

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_D \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
VL4 voltage	VL4	C1 to C4 = 0.47 μ F ^{Note 2}		VDD		V
VL2 voltage	VL2	C1 to C4 = 0.47 μ F ^{Note 2}	2/3 VL4 -	2/3 VL4	2/3 VL4 +	V
			0.1		0.1	
VL1 voltage	VL1	C1 to C4 = 0.47 μ F ^{Note 2}	1/3 VL4 -	1/3 VL4	1/3 VL4 +	V
			0.1		0.1	
Capacitor split wait time ^{Note 1}	tvwait		100			ms

Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).

2. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

- C2: A capacitor connected between $V_{\mbox{\tiny L1}}$ and GND
- C3: A capacitor connected between $V_{\mbox{\tiny L2}}$ and GND

C4: A capacitor connected between VL4 and GND

C1 = C2 = C3 = C4 = 0.47 pF±30 %



3.11 Timing Specifications for Switching Flash Memory Programming Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset must be released before the external reset is released.	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset must be released before the external reset is released.	1			ms

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and completion the baud rate setting.
- **Remark** tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.
 - $t_{\text{SU}:}$ Time to release the external reset after the TOOL0 pin is set to the low level
 - the: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)



4.2 80-pin Products

R5F10WMAAFA, R5F10WMCAFA, R5F10WMDAFA, R5F10WMEAFA, R5F10WMFAFA, R5F10WMGAFA

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP80-14x14-0.65	PLQP0080JB-E	P80GC-65-UBT-2	0.69





detail of lead end

Referance	Dimens	sion in Mill	imeters
Symbol	Min	Nom	Max
D	13.80	14.00	14.20
E	13.80	14.00	14.20
HD	17.00	17.20	17.40
HE	17.00	17.20	17.40
А			1.70
A1	0.05	0.125	0.20
A2	1.35	1.40	1.45
A3		0.25	
bp	0.26	0.32	0.38
С	0.10	0.145	0.20
L		0.80	
Lp	0.736	0.886	1.036
L1	1.40	1.60	1.80
	0°	3°	8°
е		0.65	
х			0.13
У			0.10
ZD		0.825	
ZE		0.825	

Lp





R5F10WMAAFB, R5F10WMCAFB, R5F10WMDAFB, R5F10WMEAFB, R5F10WMFAFB, R5F10WMGAFB, R5F10WMCGFB, R5F10WMCGAFB, R5W10WCGAFB, R5W10WCGAFA, R5W10WCGAFA, R5W10WCGAFA, R5W10WCGAFA, R5W10WCGAFA, R5W10WCGAFA, R5W10W

